

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 14603-007US1	Application No. 10/500079
		Applicant Jochen Kraft et al.	
		Filing Date June 23, 2004	Group Art Unit 2814

**Information Disclosure Statement
by Applicant**
(Use several sheets if necessary)

(37 CFR §1.98(b))

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
/AM/	AA	5,589,409	12/31/96	Constantin Bulucca et al			
	AB	5,962,880	10/05/99	Katsuya Oda et al			
	AC	5,693,979	12/02/97	Fumihiko Sato			
	AD	6,563,147	05/13/03	Tatsuhiko Ikeda			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
/AM/	AL	WO01/91162	11/29/01	WIPO				
	AM	04099328	03/31/92	Abstracts of Japan				
	AN	0 701 287	03/13/96	EPO				
	AO	1 263 052	12/04/02	EPO				
	AP	100 60 584	07/19/01	Germany			Abstract	

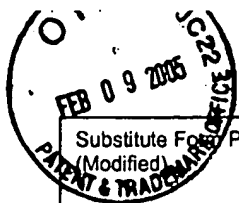
Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
/AM/	AQ	Böck, J. et al. "SiGe Bipolar Technology for Mixed Digital and Analogue RF Applications" Infineon Technologies, 2000 IEEE; 0-7803-6441-4
	AR	Gruhle, A. et al. "The Reduction of Base Dopant Outdiffusion in SiGe Heterojunction Bipolar Transistors by Carbon Doping" Applied Physics Letter 1999, Vol 75, No. 9 pp. 1311-1313 XP000868226
	AS	Ryum, B.R. et al "MBE-grown SiGe base HBT with Polysilicon-emitter and TiSi2 Base Ohmic Layer" Solid-State Electronics 1996, Vol 39, No. 11, pp 1643-1648, XP000635613
	AT	Osten, H.L. et al "The Effect of Carbon Incorporation on SiGe Heterobipolar Transistor Performance and Process Margin" Electron Devices Meeting 1997, pp 803-806 XP10265625

Examiner Signature /Anh Mai/	Date Considered 03/12/2007
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
/AM/	AU	Liu J.P. et al "Substitutional Carbon Incorporation During Si1-x-yGexCy Growth on Si(100) by Molecular-beam Epitaxy: Dependence on Germanium and Carbon" Applied Physics Letters; 2000, Vol. 76, No. 24 pp. 3546-3548

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14603-007US1Application No.
10/500,079**Information Disclosure Statement
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Applicant
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2814**U.S. Patent Documents**

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	AH							
	AI							
	AJ							
	AK							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
/AM/	AL	Translation of International Preliminary Examination Report for Application No. PCT/EP2002/014679.
	AM	
	AN	
	AO	

Examiner Signature

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